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ABSTRACT

The TPS386000-Q1 family of voltage supervisors monitors four power rails that are greater than 0.4 V and one power rail that is less than 0.4 V (including negative voltage) with a 0.25% (typical) threshold accuracy. Each of the four supervisory circuits (SVS-*n*) assert a RESET*n* or RESET*n* output signal when the SENSE*m* input voltage drops below the programmed threshold. With external resistors, the threshold of each SVS-*n* can be programmed (where n = 1, 2, 3, 4 and m = 1, 2, 3, 4L, 4H).

Each SVS-*n* has a programmable delay before releasing $\overline{\text{RESET}n}$ or RESETn. The delay time can be set from 1.4 ms to 10 seconds through the CT*n* pin connection. Only SVS-1 has an active-low manual reset (MR) input which is a logic-low input to MR that asserts RESET1 or RESET1.

SVS-4 monitors the threshold window using two comparators. The extra comparator can be configured as a fifth SVS to monitor negative voltage with the voltage-reference output, VREF.

The TPS386000-Q1 device has a very-low quiescent current of 12 mA (typical) and is available in a small, 4–mm × 4–mm, QFN-20 package.

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Pin FMEA

This application note provides a Failure Modes and Effects Analysis (FMEA) for the device pins of the TPS386000-Q1 quad-supply voltage-supervisor device with programmable delay and watchdog timer. The failure conditions covered in this document include typical failure scenarios such as short-circuit to GND, short-circuit to VCC, short-circuit to a neighboring pin, and if the pin is left open. The following tables list how these conditions affect the device. The first effect considered is whether the condition damages the pin in question or the device itself. The second effect considered is whether the device is functional under the condition. Lastly, the analysis includes a comments section that discusses how the particular condition affects the device operation.

NOTE: The first letter, *X*, of the pin name is expressed with the active-low bar.

Class	Failure Effects			
A Damage to device affects application functionality				
В	No damage to device but thermal damage must be considered			
С	No damage to device but can affect application functionality			
D	No damage to device and no affect to application functionality			

Table 1. Classification of Failure Effects

Table 2. Pin FMEA Analysis for Pin Short-Circuit to GND

Pin		Short to GND				
No.	Name	Damage	ge Functionality Comments		Class	
1	MR	NO	YES	Can affect functionality of the sub-CPU circuit that drives $\overline{\text{MR}}$ pin.		
2	CT4		YES			
3	CT3	NO		A pulldown transistor is located on each pin. If these pins are	D	
4	CT2	NO	TES	shorted to GND, the programmable delay circuit does not function correctly.	D	
5	CT1			······································		
6	SENSE4H	NO	YES		D	
7	SENSE4L					
8	SENSE3	NO	YES	The corresponding RESETn output is always asserted if the SENSEn input is shorted to GND.	D	
9	SENSE2	NO			D	
10	SENSE1					
11	NC	NO	YES	This pin has no electrical connection.	D	
12	GND	NO	YES	Normal operating condition	D	
13	VREF	NO	YES	1.2 V at 5 mA (max)		
14	VCC	NO	NO Can affect functionality No damage to device, can affect application functionality. Increases leakage.		С	
15	RESET1					
16	RESET2	NO	D YES	Whichever device is connected to the RESETn the output is always in reset if these pins are shorted to GND.	D	
17	RESET3	NU			U	
18	RESET4					
19	WDO	NO	Can affect functionality	User does not have any watchdog functionality.	С	
20	WDI	NO	Can affect functionality	User does not have any watchdog functionality.	С	

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Table 3. Pin FMEA Analysis for Pin Left Open

Pin		Short to GND					
No.	Name	Damage Functionality		Comments			
1	MR	NO	Can affect functionality	Undefined operating condition, no damage, increases leakage	С		
2	CT4				D		
3	CT3	NO	YES Leaving these pins open results in a 20-ms (typical) delay.				
4	CT2	NO		Leaving these pins open results in a 20-ms (typical) delay.			
5	CT1						
6	SENSE4H	NO	YES	Undefined operating condition (RESET4 tends to become High)	D		
7	SENSE4L	NO	YES	Undefined operating condition (RESET4 tends to become Low)	D		
8	SENSE3	NO	YES	Undefined operating condition (RESET3 tends to become Low)	D		
9	SENSE2	NO	YES	Undefined operating condition (RESET2 tends to become Low)	D		
10	SENSE1	NO	YES Undefined operating condition (RESET1 tends to become Low)		D		
11	NC	NO	O YES This pin has no electrical connection.		D		
12	GND	NO	NO NO Undefined operating condition, no damage, increases leakage		С		
13	VREF	NO	YES	Normal operating condition	D		
14	VCC	NO	NO	Undefined operating condition, no damage, increases leakage	С		
15	RESET1						
16	RESET2						
17	RESET3	NO	YES	Normal operating condition, this pin is an open-drain output.	D		
18	RESET4						
19	WDO						
20	WDI	NO	Can affect functionality	User does not have any watchdog functionality.	С		

TEXAS INSTRUMENTS

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Pin		Short to GND					
No.	Name	Damage	Functionality	Comments	Class		
1	MR	NO	YES	Can affect functionality of the sub-CPU circuit that drives $\overline{\text{MR}}$ pin.	D		
2	CT4						
3	CT3	NO	NEO.	A large current flows during wakeup, but it can be low power.	P		
4	CT2	NO	YES	TI recommends to pull these pins up to VCC with a 40k to 200k resistor.	D		
5	CT1						
6	SENSE4H	NO	YES	The RESET4 output is always be asserted if the SENSE4H input is shorted to VCC. The DC-DC or LDO that is monitored is affected.			
7	SENSE4L						
8	SENSE3		2/50	ES The DC-DC or LDO that is monitored is affected.	D		
9	SENSE2	NO	YES				
10	SENSE1						
11	NC	NO	YES	This pin has no electrical connection.			
12	GND	NO	NO	No damage to device, can affect application functionality. Increases leakage.			
13	VREF	NO	YES	1.2 V at 5 mA (max)	В		
14	VCC	NO	YES	Normal operating condition			
15	RESET1						
16	RESET2	YES	NO	D I _{RESET} < 5 mA (absolute)	А		
17	RESET3	TES			А		
18	RESET4						
19	WDO	YES	NO	I _{WDO} < 5 mA (absolute)	А		
20	WDI	NO	YES	Functionality of FPGA connected to this pin can be affected.	D		

Table 4. Pin FMEA Analysis for Pin Short-Circuit to VCC



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Table 5. Pin FMEA Analysis for Pin Short-Circuit to Neighboring Pin

Pin		Short to GND					
No.	Name	Damage	Functionality	Comments	Class		
1	MR to CT4	NO	Can affect functionality	No electric damage, increases leakage at $\overline{\text{MR}}.$ The desired delay is not achieved if these pins are shorted together.	В		
2	CT4 to CT3						
3	CT3 to CT2	NO	YES	The desired delay is not achieved if these pins are shorted together.	D		
4	CT2 to CT1						
5	CT1 to SENSE4H	NO	YES	The desired delay is not achieved if these pins are shorted together. The respective RESETn outputs do not function as desired.	D		
6	SENSE4H to SENSE4L						
7	SENSE4L to SENSE3	- NO	YES	The respective RESETn outputs do not function as desired.	D		
8	SENSE3 to SENSE2						
9	SENSE2 to SENSE1						
10	SENSE1 to NC	NO	YES		D		
11	NC to GND	NO	YES		D		
12	GND to VREF	NO	YES	1.2 V at 5 mA (max)	В		
13	VREF to VCC	NO	YES	1.2 V at 5 mA (max)	В		
14	VCC to RESET1	YES	NO	I _{RESET} < 5 mA (absolute)	А		
15	RESET1 to RESET2						
16	RESET2 to RESET3	NO	YES		С		
17	RESET3 to RESET4	INU	TEO		U		
18	RESET4 to WDO						
19	WDO to WDI	NO	Can affect functionality	Functionality of FPGA connected to this pin can be affected.	В		
20	WDI to MR	NO	Can affect functionality	Undefined operating condition, no damage, increases leakage	С		

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